

# SiC within INFN: status and perspectives

Valter Bonvicini

*INFN Trieste*

Workshop “From Silicon to SiC detectors”, LNS, 7-8 aprile 2016

# SiC properties

- SiC sensors suited for:
  - room/high-temperature and harsh environment detector operation;
  - UV photon detection (visible-blind)
- Characteristics:
  - Wide bandgap energy ( $E_g \approx 3.27$  eV)
  - High breakdown electric field ( $3 \text{ MV cm}^{-1}$ )
  - High carrier saturation drift velocity ( $2 \times 10^7 \text{ cm s}^{-1}$ )
  - High displacement atom energy (22 – 35 eV)


# Comparison between SiC and other semiconductors properties

**Table 1.** Comparison of properties of selected important materials mostly used for radiation ionizing detector realization with semiconductor 4H-SiC. Data compiled from [14, 23–25] and references therein.

Property	D	Si	Ge	GaAs	CdTe	4H-SiC
Bandgap (eV)	5.5	1.12	0.67	1.42	1.49	3.27
Relative dielectric constant	5.7	11.9	16	13.1	10	9.7
Breakdown field (MV cm <sup>-1</sup> )	10	0.3	0.1	0.4	0.5	3.0
Density (g cm <sup>-3</sup> )	3.5	2.3	5.33	5.3	5.9	3.2
Atomic number Z	6	14	32	31–33	48–52	14–6
e-h creation energy (eV)	13	3.6	2.95	4.3	4.42	7.78
Saturated electron velocity (10 <sup>7</sup> cm s <sup>-1</sup> ) at 300 K	2.2	1.0	0.6	1.2	1.0	2
Electron mobility (cm <sup>2</sup> V <sup>-1</sup> s <sup>-1</sup> ) at 300 K	1800	1300	3900	8500	1100	800
Hole mobility (cm <sup>2</sup> V <sup>-1</sup> s <sup>-1</sup> ) at 300 K	1200	460	1900	400	100	115
Threshold displacement energy (eV)	40–50	13–20	16–20	8–20	6–8	22–35
Minimum ionizing energy loss (MeV cm <sup>-1</sup> )	4.7	2.7	6	5.6		4.4

From F. Nava et al., Meas. Sci. Technol. **19** (2008) 102001

# SiC as detector material

- Potential of SiC as radiation detector has been long recognized:
  - First SiC neutron detectors > 50 years ago (*Babcock et al. 1957; Babcock & Chang 1962*)
- Poor material properties of the SiC available at that time and lack of adequate investment have hindered the development of the technology for detector fabrication until the 90ies.
- Effort concentrated on improving the properties of SiC by reducing defects produced during the crystal growing process (dislocations, micropipes, etc.)  availability of much higher quality SiC semiconductor materials
  - A parallel effort resulted in improved SiC electronics fabrication techniques

# SiC@INFN

- Currently, two initiatives within INFN – CSN5
- ClasSiC (P. Lenzi, grant for young researchers 2015)
  - Dual read-out hadronic calorimetry
  - TOF-PET with sensitivity to Cherenkov light ( $\approx$  10 ps resolution)
  - Need for single-photon sensitivity
    - Final target: device with intrinsic amplification ( $10^3 - 10^4$ )
- SiCILIA (S. Tudisco, financed as CSN5 “call” 2016)
  - SiC as material for rad-hard detectors in nuclear physics (clear motivating physics case)
    - SiC  $\Delta E$ -E telescope for ion identification and spectroscopy)
    - Need for unprecedented active volume thickness
    - Large production of large area ( $\text{cm}^2$ ) devices
    - Industrial impact

# IFD2015 (Torino, 16-18/12/2015)

- Bring together the vast INFN community involved in detector technology development: many achievements/efforts can be extremely useful for applications **different** from the starting one;
  - Times have changed (and available resources too): we cannot afford anymore duplications of R&D...
- Some strategic elements have emerged:
  - Collaboration with the industries
  - Collaboration with other Research Institutes
  - Preservation and development of the know-how and transmission to the next generations.

# Collaboration with other Research Institutes/Communities

- New technologies require collaborations
  - Some technologies are in our hands, others are not
  - Even for “our” technologies, cross-collaboration and knowledge amongst the community is crucial (e.g. this workshop)



# CLASSiC and SiCILIA



Investigate SiC detectors from complementary points of view

## CLASSiC

## SiCILIA

Light detection

Applications

Particles detection

- Complex p-n junction
- Multi-layer
- ion implantation

Junction

- Schottky
- epitaxial p-n

Thin substrates

Substrate

Thick, high purity substrates

In house CNR-IMM  
(with opportunistic  
use of ST facilities)


Manufacturing

P-n junctions @ ST  
Schottky @ FBK

P. Lenzi, IFD2015 Workshop



# SiC detectors: perspectives

- In recent years, many groups have been working on SiC R&D for a wide spectrum of applications:
  - Space (especially X-ray detectors for planetary exploration, see e.g. J.E. Lees et al., *Nucl. Instr. and Meth. in Phys. Res. A* 604 (2009) 174)
  - Laser-driven ions (e.g. TOF diagnostics at ELI), see e.g. G. Bertuccio et. al., *Appl. Surf. Sci.* 272 (2013) 128, see also G. Lanzalone's talk
  - Neutron detectors
    - Homeland security (fast n and )
    - Nuclear plants (reactor monitoring, spent fuel monitoring, ...)
    - Oil and gas prospections (nuclear geophysics)
    - Activities @ ESS
    - BNCT neutron exposure motoring

# Conclusions

- SiC stands out as one of the most promising “future” semiconductor material for radiation detectors fabrication;
- Collaboration with Industry and other Research Institutes is strategic in order to improve the technology and make it available to the INFN research community;
- In this framework, CSN5 strongly supports R&D on SiC technology;
- The rapid pace of SiC detector development and the large number of research groups involved worldwide bode well for the future of SiC detector applications.